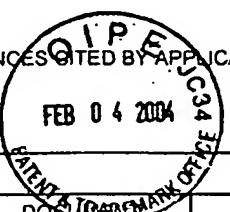


Form PTO 1449 (Modified)		DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 242612US2		SERIAL NO. 10/659,342	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Atsushi KAWAMURA			
				FILING DATE September 11, 2003		GROUP 2872 2873	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
JV	AA	6,198,562	03/06/01	HAYASHI et al.			
	AB	6,317,246	11/13/01	HAYASHI et al.			
	AC	6,185,026	02/06/01	HAYASHI et al.			
	AD	4,653,873	03/31/87	KAWAMURA			
	AE	4,372,654	02/08/83	FUJIOKA et al.			
	AF	4,277,128	07/07/81	KAWAMURA			
	AG	4,147,412	04/03/79	KAWAMURA et al.			
	AH	4,124,882	11/07/78	KAWAMURA et al.			
	AI	4,059,345	11/22/77	KAWAMURA et al.			
	AJ	3,977,761	08/31/76	KAWAZU et al.			
	AK	4,095,888	06/20/78	KAWAZU et al.			
	AL	4,527,867	07/09/85	FUJIOKA et al.			
	AM	4,576,444	03/18/86	KAWAMURA			
	AN	4,673,259	06/16/87	KAWAMURA			
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO						
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner JACK DINH					Date Considered 04/05/05		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO 1449 (Modified) FEB 04 2004 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 242612US2		SERIAL NO. 10/659,342				
APPLICANT Atsushi KAWAMURA		FILING DATE September 11, 2003		GROUP 2872 2873				
U.S. PATENT DOCUMENTS								
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS SUB CLASS	FILING DATE IF APPROPRIATE		
JD	AA	5,508,794	04/16/96	IKESUE et al.	/	/		
	AB	5,760,970	06/02/98	KAWAMURA				
	AC	5,687,401	11/11/97	KAWAMURA et al.				
	AD	5,760,973	06/02/98	KAWAMURA				
	AE	6,496,293	12/17/02	KAWAMURA				
	AF							
	AG							
	AH							
	AI							
	AJ							
	AK							
	AL							
	AM							
	AN							
	FOREIGN PATENT DOCUMENTS							
			DOCUMENT NUMBER	DATE			COUNTRY	TRANSLATION YES NO
	AO							
	AP							
	AQ							
	AR							
	AS							
	AT							
	AU							
	AV							
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)								
	AW							
	AX							
	AY							
	AZ							
					<input type="checkbox"/> Additional References sheet(s) attached			
Examiner JACK DINH					Date Considered 04/05/05			
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LIST OF REFERENCES CITED BY APPLICANT 				APPLICANT Atsushi KAWAMURA			
				FILING DATE September 11, 2003		GROUP 2873	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	2002-214550	07/31/2002	JAPAN (with English Abstract)			X
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
JP	AW	R. W. CORRIGAN, et al., Society for Information Display Symposium, http://www.siliconlight.com/htmlpgs/glvtechframes/glvmainframeset.html , pages 1-4, "CALIBRATION OF A SCANNED LINEAR GRATING LIGHT VALVE™ PROJECTION SYSTEM", May 18, 1999					
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner JACK DINH					Date Considered 04/05/05		
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